

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Keizo Yamada

Serial No.: 09/865,528

Group Art Unit: 2829

Filed: May 29, 2001

Examiner: Nguyen, Vinh P.

For: SEMICONDUCTOR DEVICE TEST METHOD AND SEMICONDUCTOR DEVICE  
TESTER

Honorable Commissioner of Patents  
Washington, D.C. 20231

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated December 26, 2002, please amend the above-identified application as follows:

IN THE CLAIMS:

Please amend claims 1 and 14 as follows:

1. (Amended) A semiconductor device tester comprising:
- electron beam irradiation means for irradiating a test sample with an electron beam;
- current measuring means for measuring current generated in said test sample by said electron beam;
- memory means for storing current waveforms for each of a plurality of test samples, wherein said current waveforms comprise variations of said measured current for each of said plurality of test samples in correspondence with irradiation positions of said electron beam; and

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02 FC:1201

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